

<b>Notice of References Cited</b>		Application/Control No. 10/526,059	Applicant(s)/Patent Under Reexamination ELLISON ET AL.	
		Examiner Nicole T. Gugliotta	Art Unit 4174	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,180,958 B1	01-2001	Cooper, Jr., James Albert	257/77
*	C	US-5,043,773	08-1991	Precht et al.	257/77
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	K	US-			
	L	US-			
	M	US-			

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#### NON-PATENT DOCUMENTS

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	U	Kordina et al. "Long minority carrier lifetime in 6H SiC grown by chemical vapor deposition". Appl. Phys. Lett. 66 (2), 9 January 1995. pgs 189 - 191.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.